



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Tomoyoshi KUSHIDA

Group Art Unit: 2811

Application No.: 09/435,766

Examiner:

S. Loke

22/F FJONES 10-11-02

Filed: November 8, 1999

Docket No.: 104361

For:

SEMICONDUCTOR DEVICE

AMENDMENT UNDER 37 C.F.R. §1.111

Director of the U.S. Patent and Trademark Office Washington, D.C. 20231

Sir:

In reply to the June 3, 2002 Office Action, and the interview held September 24, 2002, the period for reply extended to October 3, 2002, by a Petition for Extension of Time filed herewith, please amend the above-identified application as follows:

## IN THE CLAIMS:

Please replace claims 12 and 28-30 as follows:

12. (Five Times Amended) A semiconductor device comprising:

a substrate having a first conductive type;

a drift region having the first conductive type and disposed on the substrate;

a channel region having a second/conductive type different from the first

conductive type and provided on the drift region;

a gate region provided so as to surround at least the channel region via an

insulation film; and

a source region having the first conductive type and provided on the channel region, the source region is located substantially at a center of the channel region, wherein an impurity concentration of the channel region is equal to or less than an impurity concentration in the drift region, and/a depletion layer forms over the entire channel region sandwiched between the gate region when a zero bias is applied to the gate region